

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/840,192	FUJIKAWA ET AL.
Examiner	Art Unit	
EDMUND H. LEE	1791	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
264	259,255	3/30/2009	EHL
264	319,293	3/30/2009	EHL
264/	220	3/30/2009	EHL